

<b>Notice of References Cited</b>	Application/Control No. 10/680,345	Applicant(s)/Patent Under Reexamination AMYOT ET AL.	
	Examiner Brian P. Whipple	Art Unit 2196	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0065942 A1	04-2003	Lineman et al.	713/201
*	B	US-6,327,618 B1	12-2001	Ahlstrom et al.	709/223
*	C	US-6,529,954 B1	03-2003	Cookmeyer et al.	709/224
*	D	US-6,940,847 B1	09-2005	Glitho et al.	370/352
*	E	US-2002/0184535 A1	12-2002	Moaven et al.	713/202
*	F	US-2002/0198892 A1	12-2002	Rychel et al.	707/102
*	G	US-2002/0103895 A1	08-2002	Chiang, Kevin Kang-Yue	709/224
*	H	US-6,484,261 B1	11-2002	Wiegel, Scott L.	726/11
*	I	US-6,880,005 B1	04-2005	Bell et al.	709/225
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Gorse; The Feature Interaction Problem: Automatic Filtering of Incoherences & Generation of Validation Test Suites at the Design Stage; September, 2000; Pg. 67
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.